

**1x2Mx32bit DRAM Card**  
**2x2Mx32bit DRAM Card**

**MF18M1-J57ATXX**  
**MF116M-J57ATXX**

Connector Type

**Two-piece 88-pin**

**DESCRIPTION**

These DRAM CARDS are developed based on JEIDA DRAM CARD GUIDELINE Ver. 2.1. These cards are made using industry standard 2 M × 8 Dynamic RAM and interface IC's in TSOP.

**FEATURES**

- Operating Voltage  $V_{CC}=3.3V \pm 5\%$
- All inputs except RAS inputs are buffered.
- Standard card size : 54mm (W) × 85.6mm (L) × 3.3mm (T)
- 88pin 2 piece connector type.
- RAS only refresh mode, CAS before RAS refresh mode and Page mode functions are available.
- Extended refresh is available. (128ms/2048cycle)

**APPLICATIONS**

Main/expansion memory unit for Personal Computer, Laser-Printer, FAX etc.

**PRODUCT LIST**

Product No.	Item Type name	Memory capacity	Data Bus width (bits)	Access time (tRAC) (ns)	Connector type	Number of pins	Outline drawing
No. 1	MF18M1-J57ATXX	8 MB	32	70	Two-piece	88	88P-002
No. 2	MF116M-J57ATXX	16MB	(without parity)				

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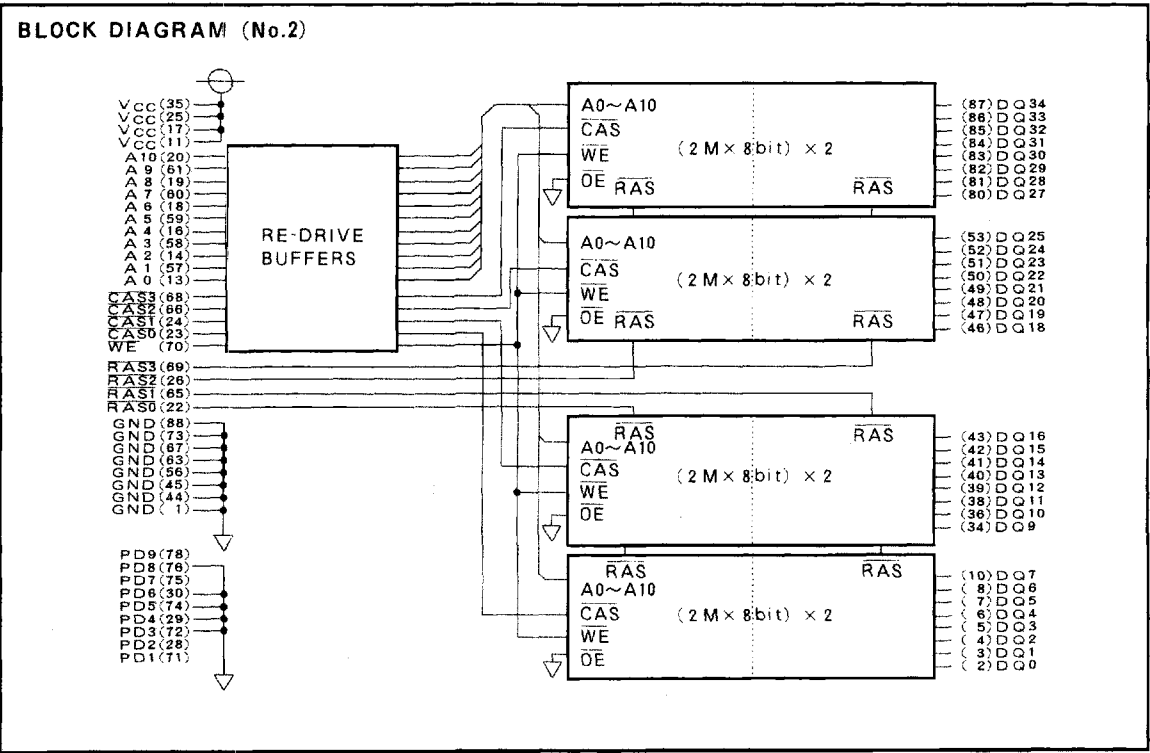
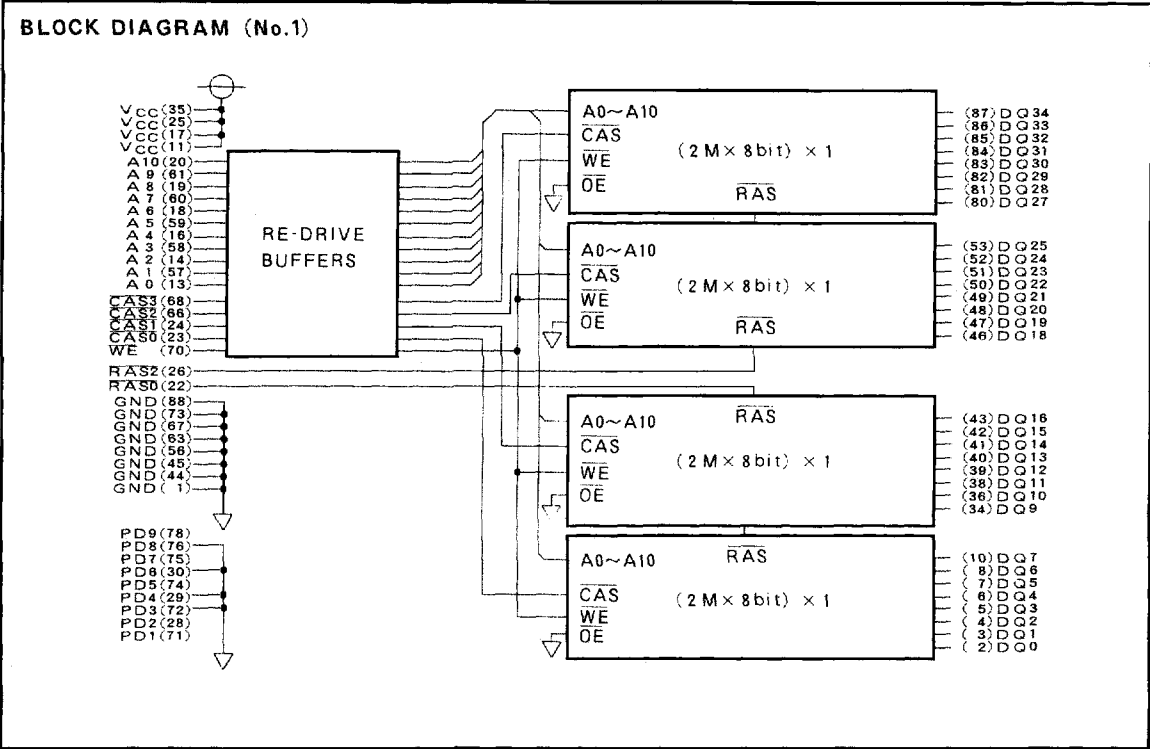
PIN ASSIGNMENT

Pin No.	Symbol	Function	Pin No.	Symbol	Function	
1	GND	Ground	45	GND	Ground	
2	DQ 0	Data I/O	46	DQ18	Data I/O	
3	DQ 1		47	DQ19		
4	DQ 2		48	DQ20		
5	DQ 3		49	DQ21		
6	DQ 4		50	DQ22		
7	DQ 5		51	DQ23		
8	DQ 6		52	DQ24		
9	NC		No connection	53		DQ25
10	DQ7	Data I/O	54	NC	No connection	
11	Vcc	Power supply voltage	55	NC	No connection	
12	NC	No connection	56	GND	Ground	
13	A 0	Address input	57	A 1	Address input	
14	A 2		58	A 3		
15	NC	No connection	59	A 5		
16	A 4	Address input	60	A 7		
17	Vcc	Power supply voltage	61	A 9		
18	A 6	Address input	62	NC	No connection	
19	A 8		63	GND	Ground	
20	A10		64	NC	No connection	
21	NC	No connection	65	<u>RAS 1</u>	Row address strobe 1 (NC for No. 1)	
22	<u>RAS 0</u>	Row address strobe 0	66	<u>CAS 2</u>	Column address strobe 2	
23	<u>CAS 0</u>	Column address strobe 0	67	GND	Ground	
24	<u>CAS 1</u>	Column address strobe 1	68	<u>CAS 3</u>	Column address strobe 3	
25	Vcc	Power supply voltage	69	<u>RAS 3</u>	Row address strobe 3 (NC for No. 1)	
26	<u>RAS 2</u>	Row address strobe 2	70	WE	Write enable	
27	NC	No connection	71	PD 1	Presence detect 1	
28	PD 2	Presence detect 2	72	PD 3	Presence detect 3	
29	PD 4	Presence detect 4	73	GND	Ground	
30	PD 6	Presence detect 6	74	PD 5	Presence detect 5	
31	NC	No connection	75	PD 7	Presence detect 7	
32	NC		76	PD 8	Presence detect 8	
33	NC	No connection	77	NC	No connection	
34	DQ 9	Data I/O	78	PD 9	Presence detect 9	
35	Vcc	Power supply voltage	79	NC	No connection	
36	DQ10	Data I/O	80	DQ27	Data I/O	
37	NC	No connection	81	DQ28		
38	DQ11	Data I/O	82	DQ29		
39	DQ12		83	DQ30		
40	DQ13		84	DQ31		
41	DQ14		85	DQ32		
42	DQ15		86	DQ33		
43	DQ16		87	DQ34		
44	GND		Ground	88	GND	Ground

PD Pin Table

Product No.	PD 1	PD 2	PD 3	PD 4	PD 5	PD 6	PD 7	PD 8	PD 9
No. 1	NC	NC	GND	GND	NC	GND	NC	GND	NC
No. 2	NC	NC	GND	GND	GND	GND	NC	GND	NC

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FUNCTION TABLE

Operation	input					input/output		Refresh	Note
	$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	$\overline{\text{WE}}$	Row Address	Column Address	input	output		
Read	ACT	ACT	NAC	APD	APD	OPN	VLD	YES	Page mode identical
Early write	ACT	ACT	ACT	APD	APD	VLD	OPN	YES	
$\overline{\text{RAS}}$ only refresh	ACT	NAC	DNC	APD	DNC	DNC	OPN	YES	
$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh	ACT	ACT	NAC	DNC	DNC	DNC	OPN	YES	
Self refresh	ACT	ACT	NAC	DNC	DNC	DNC	OPN	YES	
Standby	NAC	DNC	DNC	DNC	DNC	DNC	OPN	NO	

Note 1 : ACT : active, NAC : nonactive, DNC : don't care, VLD : valid, APD : applied, OPN : open  
 Don't be active the even and odd No. RASs at the same time. (Read/Early write cycle only)

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings		Unit
			No. 1	No. 2	
$V_{CC}$	Supply voltage		-0.5~4.6		V
$V_I$	Input voltage	With respect to GND	-0.5~4.6		V
$V_O$	Output voltage		-0.5~4.6		V
$I_O$	Output current		50		mA
$P_d$	Power dissipation	$T_a = 25^\circ\text{C}$	4	8	W
$T_{opr}$	Operating temperature		0~55		$^\circ\text{C}$
$T_{stg}$	Storage temperature		-40~80		$^\circ\text{C}$

RECOMMENDED OPERATING CONDITIONS ( $T_a = 0 \sim 55^\circ\text{C}$ , unless otherwise noted): (Note 2)

Symbol	Parameter	Limits			Unit
		Min.	Typ.	Max.	
$V_{CC}$	Supply voltage	3.135	3.3	3.465	V
GND	Supply voltage	0	0	0	V
$V_{IH}$	High input voltage	2.0		$V_{CC}$	V
$V_{IL}$	Low input voltage	0		0.8	V

Note 2 : With respect to GND

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ELECTRICAL CHARACTERISTICS ( $T_a = 0 \sim 55^\circ\text{C}$ ,  $V_{CC} = 3.3\text{V} \pm 5\%$ ,  $GND = 0\text{V}$ ): (Note 3)

Symbol	Parameter	Test condition	Limits				Unit	
			Min.		Typ.	Max.		
			No. 1	No. 2		No. 1		No. 2
$V_{OH}$	High output voltage	$I_{OH} = -2\text{ mA}$	2.4			$V_{CC}$		V
$V_{OL}$	Low output voltage	$I_{OL} = 2\text{ mA}$	0			0.4		V
$I_{OZ}$	Off-stage output current	$0\text{ V} \leq V_{OUT} \leq V_{CC}$	-10	-20		10	20	$\mu\text{A}$
$I_I$	Input current	$0\text{ V} \leq V_{IN} \leq V_{CC}$ Other input pins = 0 V	-20	-20		20	20	$\mu\text{A}$
$I_{CC1(AV)}$	Average supply current from $V_{CC}$ , operating (Note 4, 5, 6)	$\overline{RAS}$ , $\overline{CAS}$ cycling $t_{RC} = t_{WC} = \text{min}$ , output open				450	460	mA
$I_{CC2(AV)}$	Supply current from $V_{CC}$ , standby (Note 7)	$\overline{RAS} = \overline{CAS} \geq V_{CC} - 0.2\text{V}$ , other input pins $\geq V_{CC} - 0.2\text{V}$ or $\leq 0.2\text{V}$ , output open				3.0	5.0	mA
$I_{CC3(AV)}$	Average supply current from $V_{CC}$ , refreshing (Note 4, 6)	$\overline{RAS}$ cycling, $\overline{CAS} = V_{IH}$ $t_{RC} = \text{min}$ , output open				500	990	mA
$I_{CC4(AV)}$	Average supply current from $V_{CC}$ , Page-Mode (Note 4, 5, 6)	$\overline{RAS} = V_{IL}$ , $\overline{CAS}$ cycling $t_{RC} = \text{min}$ , output open				320	340	mA
$I_{CC6(AV)}$	Average supply current from $V_{CC}$ , $\overline{CAS}$ before $\overline{RAS}$ refresh mode (Note 4, 6)	$\overline{CAS}$ before $\overline{RAS}$ refresh cycling $t_{RC} = \text{min}$ , output open				490	970	mA
$I_{CC8(AV)}$	Average supply current from $V_{CC}$ , Extended refresh mode (Note 7)	$\overline{CAS}$ before $\overline{RAS}$ refresh cycling $WE \geq V_{CC} - 0.2\text{V}$ other input pins $\geq V_{CC} - 0.2\text{V}$ or $\leq 0.2\text{V}$ , output open $t_{RC} = 62.5\ \mu\text{s}$ ( $t_{RAS} = t_{RASmin} \sim 1\ \mu\text{s}$ )				7.0	9.0	mA
$I_{CC9(AV)}$	Average supply current from $V_{CC}$ , Self refresh mode (Note 7)	$\overline{RAS} = \overline{CAS} \leq 0.2\text{V}$ , $WE \geq V_{CC} - 0.2\text{V}$ output open				7.0	9.0	mA

Note 3 : Current flowing into a CARD is positive, out is negative.

4 :  $I_{CC1(AV)}$ ,  $I_{CC3(AV)}$ ,  $I_{CC4(AV)}$  and  $I_{CC6(AV)}$  are dependent on cycle rate.

Specified values are obtained at the fastest cycle rate.

5 :  $I_{CC1(AV)}$  and  $I_{CC4(AV)}$  are dependent on output loading.

Specified values are obtained with the outputs open.

6 : Column Address can be changed once or less while  $\overline{RAS} = V_{IL}$  and  $\overline{CAS} = V_{IH}$ .

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SWITCHING CHARACTERISTICS ( $T_a = 0 \sim 55^\circ\text{C}$ ,  $V_{CC} = 3.3\text{V} \pm 5\%$ ,  $GND = 0\text{V}$ ): (Note 7)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tCAC	Access time from $\overline{\text{CAS}}$ (Note 8, 9)		27	ns
tRAC	Access time from $\overline{\text{RAS}}$ (Note 8, 10)		70	ns
tCAA	Column Address access time (Note 8, 11)		42	ns
tOFF	Output disable time after $\overline{\text{CAS}}$ high (Note 12)	0	27	ns

Note 7 : An initial pause of 500  $\mu\text{sec}$  is required after power-up followed by any 8  $\overline{\text{RAS}}$  or  $\overline{\text{RAS}}/\overline{\text{CAS}}$  cycles before proper device operation is achieved. Note that  $\overline{\text{RAS}}$  may be cycled during the initial pause. And any 8  $\overline{\text{RAS}}$  or  $\overline{\text{RAS}}/\overline{\text{CAS}}$  cycles are required after prolonged periods of  $\overline{\text{RAS}}$  inactivity before proper device operation is achieved.

8 : Measured with a load circuit equivalent to 2 TTL loads and 100pF.

9 : Assume that  $t_{\text{RCD}} \geq t_{\text{RCD(max)}}$  and  $t_{\text{ASC}} \geq t_{\text{ASC(max)}}$ .

10 : Assume that  $t_{\text{RCD}} \leq t_{\text{RCD(max)}}$  and  $t_{\text{RAD}} \leq t_{\text{RAD(max)}}$ .

11 : Assume that  $t_{\text{RAD}} \geq t_{\text{RAD(max)}}$  and  $t_{\text{ASC}} \leq t_{\text{ASC(max)}}$ .

12 : tOFF(max) define the time at which the output achieves the high impedance state (No. 1 :  $|I_{\text{out}}| \leq 10\ \mu\text{A}$ , No. 2 :  $|I_{\text{out}}| \leq 20\ \mu\text{A}$ ) and are not reference to  $V_{\text{OH(min)}}$  or  $V_{\text{OL(max)}}$ .

TIMING REQUIREMENTS ( $T_a = 0 \sim 55^\circ\text{C}$ ,  $V_{CC} = 3.3\text{V} \pm 5\%$ ,  $GND = 0\text{V}$ ): (Note 13, 14)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
tREF	Refresh cycle time		32	ms
tREF	Refresh cycle time ( $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycling)		128	ms
tRP	$\overline{\text{RAS}}$ high pulse width	50		ns
tRCD	Delay time, $\overline{\text{RAS}}$ low to $\overline{\text{CAS}}$ low (Note 15)	20	43	ns
tCRP	Delay time, $\overline{\text{CAS}}$ high to $\overline{\text{RAS}}$ low (Note 16)	17		ns
tRPC	Precharge to $\overline{\text{CAS}}$ active time.	0		ns
tCPN	$\overline{\text{CAS}}$ high pulse width	10		ns
tRAD	Column address delay time from $\overline{\text{RAS}}$ low (Note 17)	17	28	ns
tASR	Row address setup time before $\overline{\text{RAS}}$ low	10		ns
tASC	Column address setup time before $\overline{\text{CAS}}$ low (Note 18)	5	10	ns
tRAH	Row address hold time after $\overline{\text{RAS}}$ low	10		ns
tCAH	Column address hold time after $\overline{\text{CAS}}$ low	15		ns
tT	Transition time (Note 19)	3	50	ns

Note 13 : The timing requirements are assumed  $t_T = 5\text{ns}$ .

14 :  $V_{\text{IH(min)}}$  and  $V_{\text{IL(max)}}$  are reference levels for measuring timing of input signals.

15 : tRCD(max) is specified as a reference point only.

If  $t_{\text{RCD}} \geq t_{\text{RCD(max)}}$ , access time is defined as tCAC and tCAA.

16 : tCRP requirement is applicable for all  $\overline{\text{RAS}}/\overline{\text{CAS}}$  cycles.

17 : tRAD(max) is specified as a reference point only.

If  $t_{\text{RAD}} \geq t_{\text{RAD(max)}}$  and  $t_{\text{ASC}} \leq t_{\text{ASC(max)}}$ , access time is assumed by tCAA for read cycle.

18 : tASC(max) is specified as a reference point only of address access time.

19 : tT is measured between  $V_{\text{IH(min)}}$  and  $V_{\text{IL(max)}}$ .

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Read and Refresh Cycles

Symbol	Parameter	Limits		Unit
		Min.	Max.	
t <sub>RC</sub>	Read cycle time	130		ns
t <sub>RAS</sub>	RAS low pulse width	70	10000	ns
t <sub>CAS</sub>	CAS low pulse width	20	10000	ns
t <sub>CSH</sub>	CAS hold time after RAS low	70		ns
t <sub>RSH</sub>	RAS hold time after CAS low	27		ns
t <sub>RSC</sub>	Read setup time before CAS low	5		ns
t <sub>RCH</sub>	Read hold time after CAS high	0		ns
t <sub>RRH</sub>	Read hold time after RAS high	10		ns

Write Cycle (Early Write)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
t <sub>WC</sub>	Write cycle time	130		ns
t <sub>RAS</sub>	RAS low pulse width	70	10000	ns
t <sub>CAS</sub>	CAS low pulse width	20	10000	ns
t <sub>CSH</sub>	CAS hold time after RAS low	70		ns
t <sub>RSH</sub>	RAS hold time after CAS low	27		ns
t <sub>WCS</sub>	Write setup time before CAS low	5		ns
t <sub>WCH</sub>	Write hold time after CAS low	15		ns
t <sub>DS</sub>	Data setup time	10		ns
t <sub>DH</sub>	Data hold time after CAS low	22		ns

Page Mode Cycle (Read, Early Write)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
t <sub>PC</sub>	Read, Write cycle time	55		ns
t <sub>CP</sub>	CAS high pulse width	10		ns
t <sub>TRAS</sub>	RAS low pulse width ( Note 20)	125	100000	ns

Note 20 : t<sub>TRAS</sub>(min) is specified by the following formula as two cycles of CAS input are executed.  
 $t_{TRAS}(min) = t_{CSH}(min) + t_{PC}(min)$ .

CAS before RAS Refresh Cycle (Note 21)

Symbol	Parameter	Limits		Unit
		Min.	Max.	
t <sub>CSR</sub>	CAS setup time for CAS before RAS refresh	20		ns
t <sub>CHR</sub>	CAS hold time for CAS before RAS refresh	15		ns

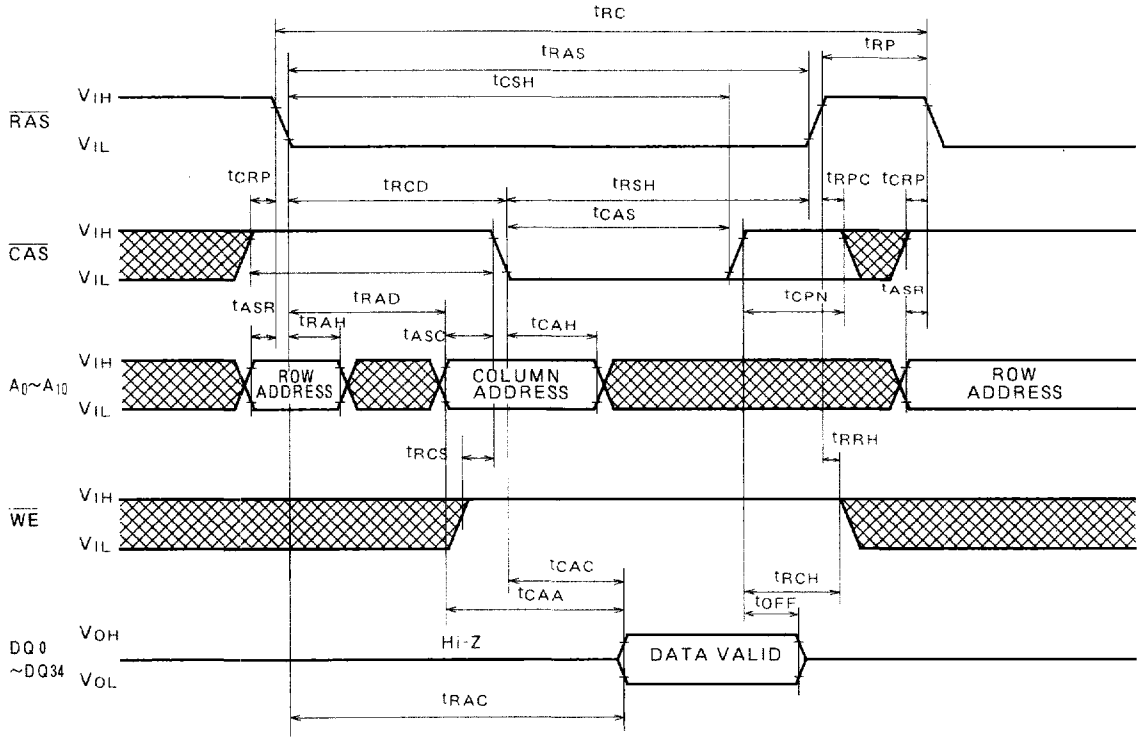
Note 21 : Eight or more CAS before RAS cycles are necessary for proper operation of CAS before RAS refresh mode.


Self Refresh Cycle

Symbol	Parameter	Limits		Unit
		Min.	Max.	
t <sub>RASS</sub>	RAS low pulse width	100		μs
t <sub>RPS</sub>	CAS high pulse width	130		ns
t <sub>CHS</sub>	RAS hold time after RAS high	-50		ns

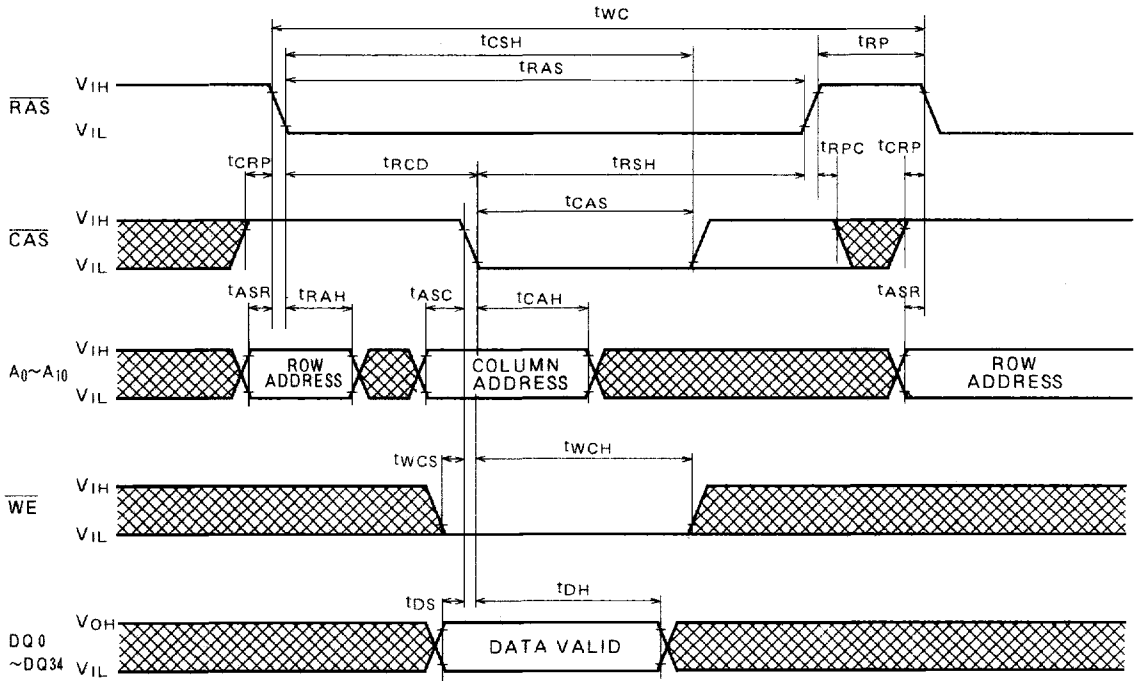
TIMING DIAGRAMS (Note 22)

Read Cycle



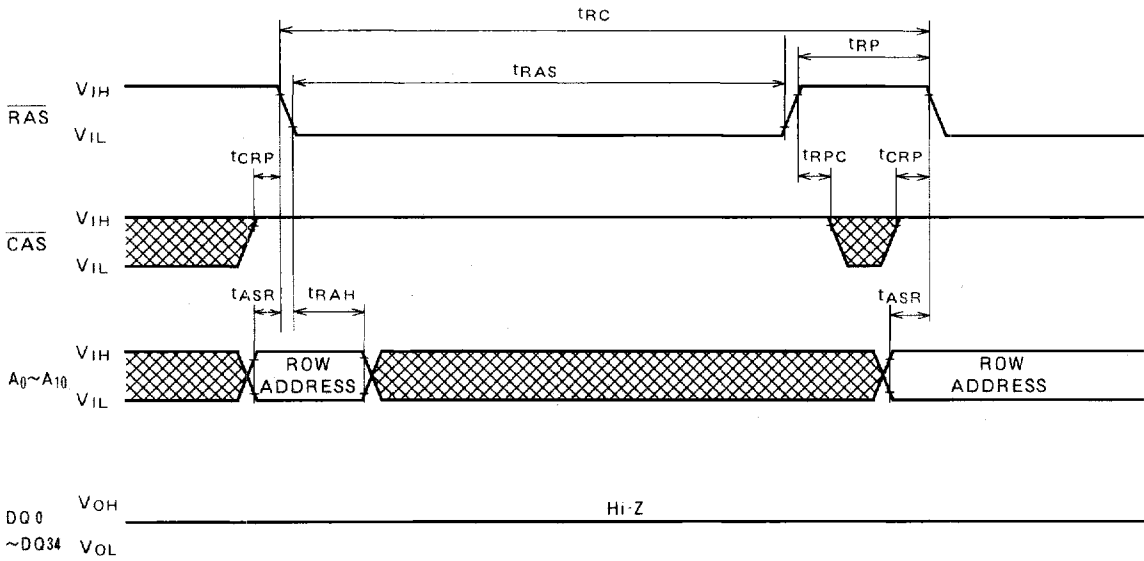
Note 22 :  Indicates the don't care input.

Early Write Cycle



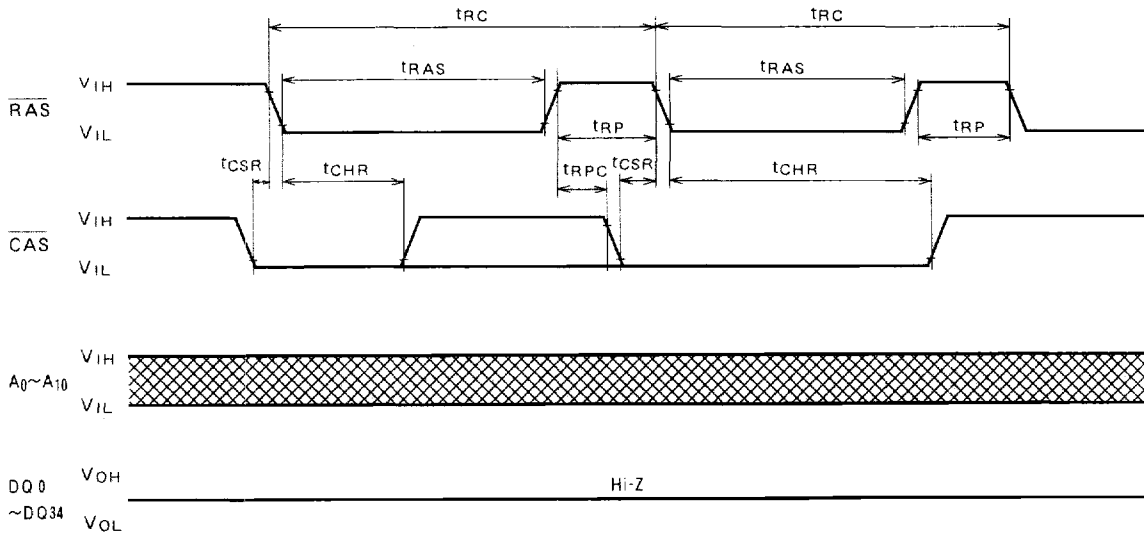
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**RAS only Refresh Cycle** (Note 23)



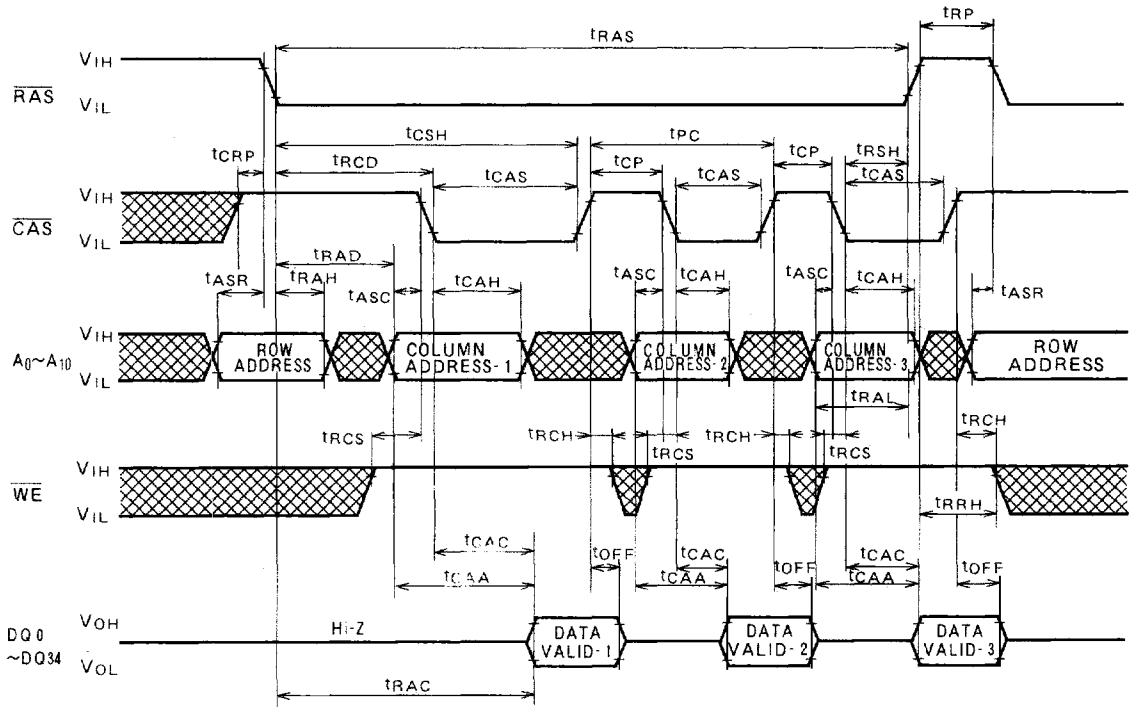
Note 23 :  $\overline{WE} = \text{don't care.}$

**CAS before RAS Refresh Cycle** (Note 24)

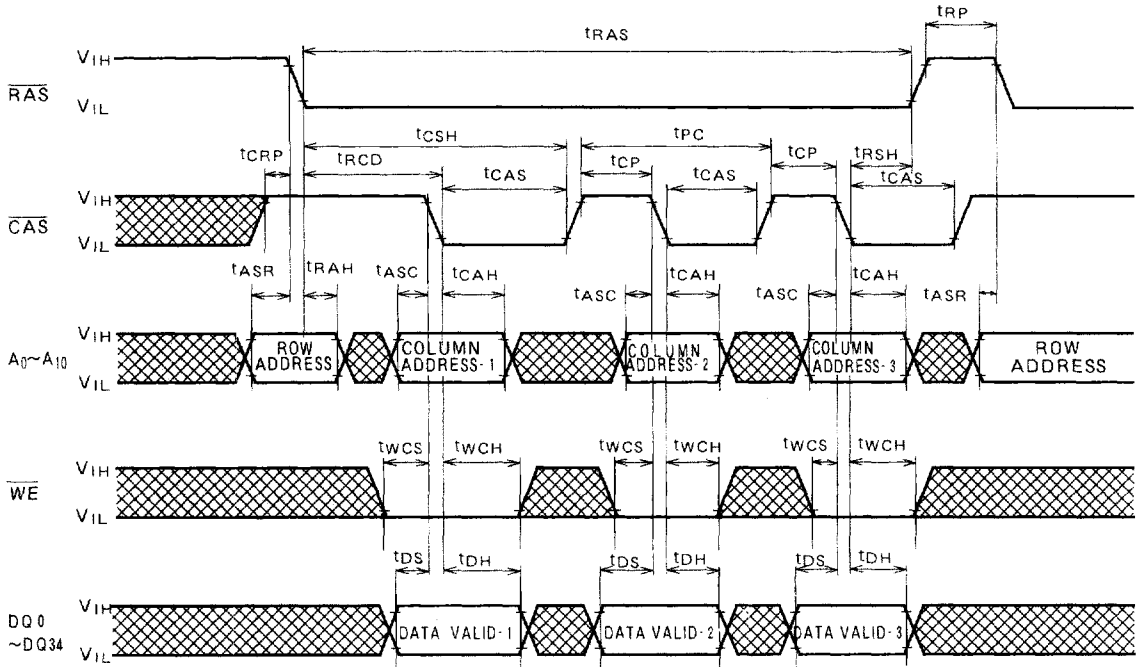


Note 24 :  $\overline{WE} = V_{IH}$

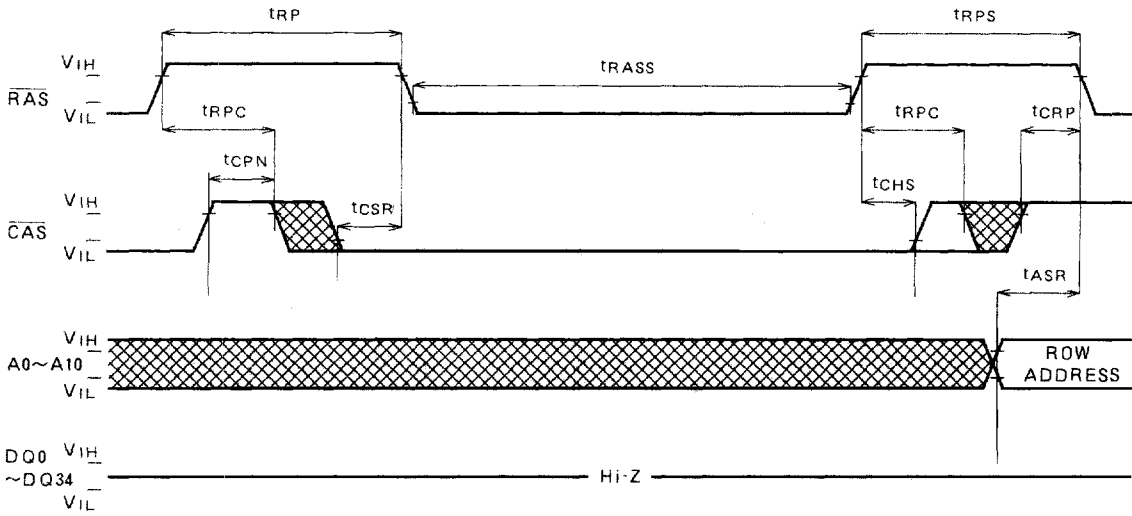
Page-Mode Read Cycle



Page-Mode Early Write Cycle



Self Refresh Cycle (Note 25, 26)

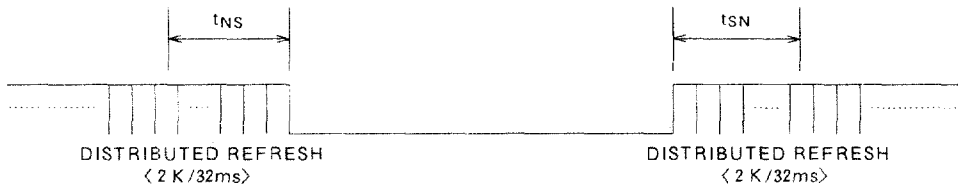


Note 25 :  $\overline{WE} = V_{IH}$

**Note 26 : SELF REFRESH ENTRY & EXIT CONDITIONS**

(1) In case of distributed refresh

The last/first full refresh cycles (2K) must be made within  $t_{NS}/t_{SN}$  before/after self refresh, on the condition of  $t_{NS} \leq 32\text{ms}$  and  $t_{SN} \leq 32\text{ms}$ .



(2) In case of burst refresh

The last/first full refresh cycles (2K) must be made within  $t_{NS}/t_{SN}$  before/after self refresh, on the condition of  $t_{NS} + t_{SN} \leq 32\text{ms}$ .

